Design Considerations for the Characterization of Capacitors

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Background

Background

Purpose

Background

Purpose

Instrumentation

Background

Purpose

Instrumentation

Regression

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Modeling

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Conclusion

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Future Work



Background

- 2011 ARPA-E grant to Dr. Welsch.
- Titanium capacitors to replace tantalum.
- Availability, cost, energy and power density.

Purpose

- Design instrumentation for Ti capacitors.
- Characterize capacitor parameters.

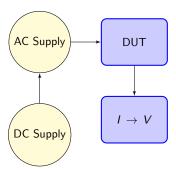
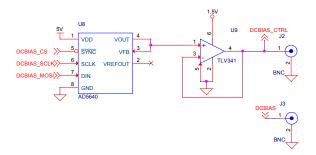
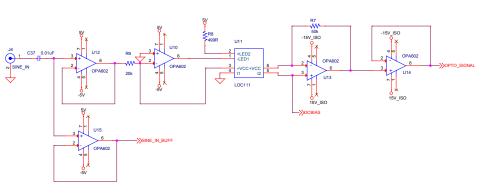
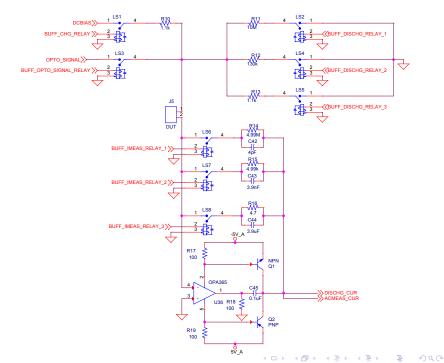
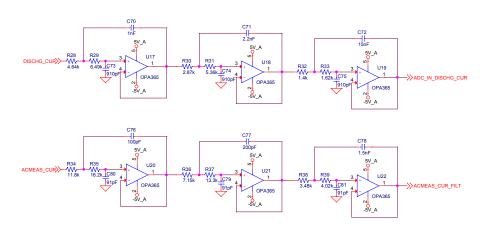


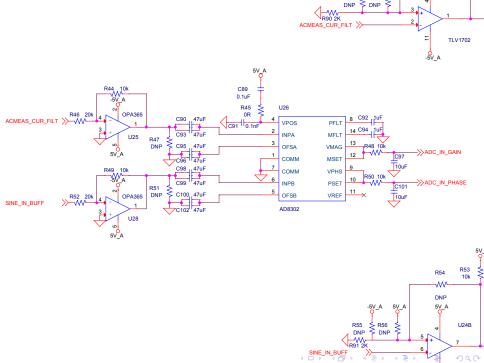
Figure: Circuit Flow Chart

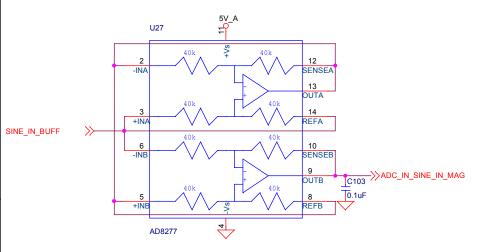




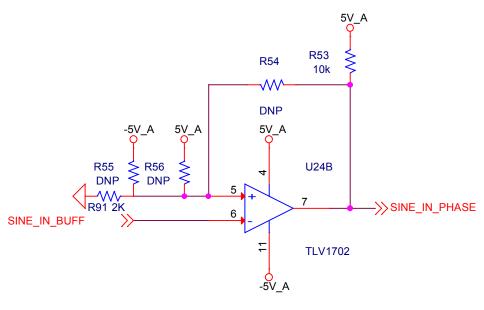








MAGNITUDE



PHASE

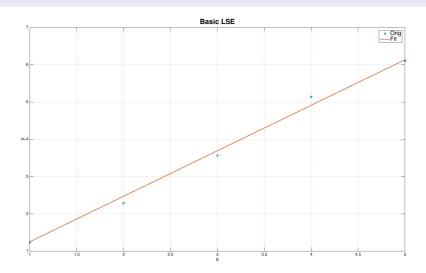


Figure: Basic LSE

Basic Regression

$$y = a_0 + a_1 x \tag{1}$$

$$E^{2} = \sum_{i=1}^{n} (y_{i} - y)^{2}$$
 (2)

$$E^{2} = \sum_{i=1}^{n} (y_{i} - (a_{0} + a_{1}x_{i}))^{2}$$
 (3)

$$\frac{\partial E^2}{\partial a_0} = 0 = \sum_{i=1}^n (-2y_i + 2a_0 + 2a_1x_i) \tag{4}$$

$$\frac{\partial E^2}{\partial a_1} = 0 = \sum_{i=1}^n (-2y_i x_i + 2a_0 x_i + 2a_1 x_i^2)$$
 (5)

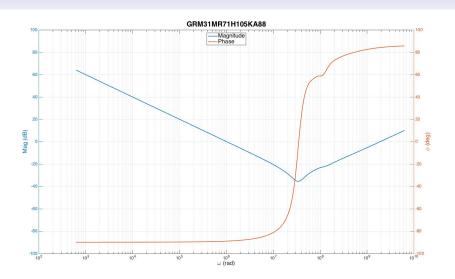


Figure: GRM31MR71H105KA88 Capacitor Data [3]



$$G(s) = \frac{A_0 + A_1 s + A_2 s^2 + \dots + A_n s^n}{B_0 + B_1 s + B_2 s^2 + \dots + B_m s^m} [1][Eq. 3]$$
 (6)

$$\lambda_h = \sum_{k=0}^{m} \omega_k^h [1] [Eq. 15]$$
 (7)

$$S_h = \sum_{k=0}^{m} \omega_k^h R_k \ [1][Eq. \ 16] \tag{8}$$

$$T_h = \sum_{k=0}^{m} \omega_k^h I_k \ [1][Eq. \ 17] \tag{9}$$

$$U_h = \sum_{k=0}^{m} \omega_k^h (R_k^2 + I_k^2) [1] [Eq. 18]$$
 (10)

$$M = \begin{bmatrix} \lambda_0 & 0 & -\lambda_2 & 0 & T_1 & S_2 \\ 0 & \lambda_2 & 0 & -\lambda_4 & -S_2 & T_3 \\ \lambda_2 & 0 & -\lambda_4 & 0 & T_3 & S_4 \\ 0 & \lambda_4 & 0 & -\lambda_6 & -S_4 & T_5 \\ T_1 & -S_2 & -T_3 & S_4 & U_2 & 0 \\ S_2 & T_3 & -S_4 & -T_5 & 0 & U_4 \end{bmatrix}$$
(11)

$$N = \begin{bmatrix} A_0 \\ A_1 \\ A_2 \\ A_3 \\ \vdots \\ B_1 \\ B_2 \\ B_3 \\ \vdots \end{bmatrix} [1][Eq. \ 21b] \quad (12) \qquad C = \begin{bmatrix} S_0 \\ T_1 \\ S_2 \\ T_3 \\ \vdots \\ 0 \\ U_2 \\ 0 \\ \vdots \end{bmatrix} [1][Eq. \ 21c]$$

$$MN = C [1][Eq. 20]$$
 (14)

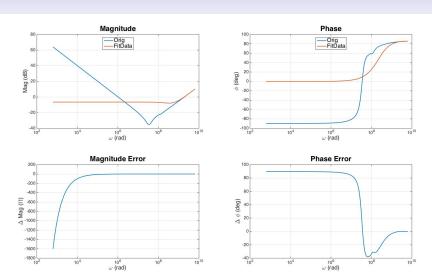


Figure: Levy's Technique



$$W_{kL} = \frac{1}{|Q(jw_k)_{L-1}|^2} [2]$$
 (15)

$$E = \sum_{k=1}^{n} |\epsilon'_{k}|^{2} W_{kL} [2] [Eq. 7]$$
 (16)

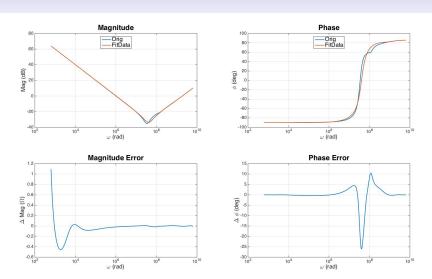


Figure: LSE + Iteration

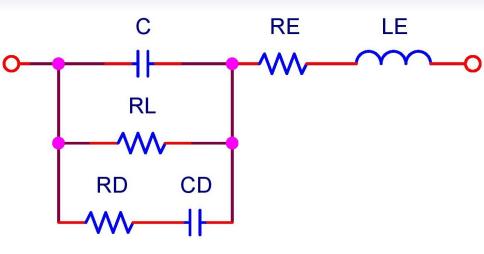


Figure: 6 Term Model

$$\bar{Z}(s) = \frac{(R_E + R_L) + (L_E + C_D R_D R_E + C_D R_D R_L + C R_E R_L + C_D R_E R_L)s}{1 + (C_D R_D + C R_L + C_D R_L)s + C C_D R_D R_L s^2} + \frac{(C_D L_E R_D + C L_E R_L + C_D L_E R_L + C C_D R_D R_E R_L)s^2 + C C_D L_E R_D R_L s^3}{1 + (C_D R_D + C R_L + C_D R_L)s + C C_D R_D R_L s^2}$$
(17)

$$\bar{Z}(s) = \frac{a_0 + a_1 s + a_2 s^2 + a_3 s^3}{b_0 + b_1 s + b_2 s^2}$$
(18)

(18)

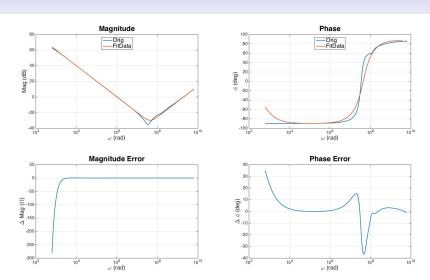


Figure: 6 Term Model: Bad Initilization



$a_0 = 5.9991E^{+03}$			
$a_1 = 1.7934E^{-04}$		$C = -8.2563E^{-10}$	
$a_2 = 3.3158E^{-12}$		$R_E = 3.1886E^{-01}$	
$a_3 = 6.8295 E^{-22}$	(19)	$L_E = 4.8551E^{-10}$	(20)
$b_0 = 1.0000$		$R_L = 4.8551E^{-10}$	(20)
$b_1 = 5.9057E^{-03}$		$C_D = 9.8536E^{-07}$	
$b_2 = 1.4067E^{-12}$		$R_D = -2.8824E^{-01}$	

$$a_{0} = 1$$
 $a_{1} = 1$
 $a_{2} = 1$
 $a_{3} = 1$
 $b_{0} = 1$
 $b_{1} = 0$
 $c = INF$
 $c = INF$
 $c = INF$
 $c = INF$
 $c = IND$
 $c = IND$

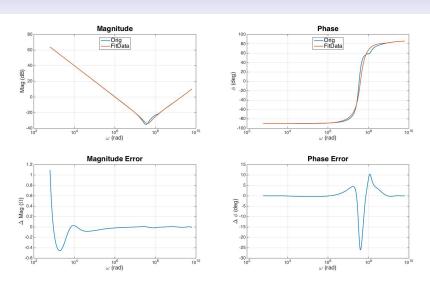


Figure: 6 Term Model: Good Initilization



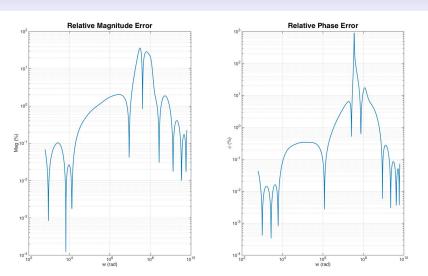


Figure: 6 Term Model: Relative Error



Conclusion

Circuit Capabilities:

- Decay Curve
- Impedance

Measurement Range:

- DC bias range 0→500V.
- Frequency Range of 100Hz→100kHz.

Regression Accuracy:

- Accurrate outside of resonance.
- 2Ω and 2°.
- < 5%.

Future Work

- Build the circuit and validate against the stated capabilities and accuracy.
- Increase the available frequency range for the measurement circuitry.
- Add additional fail-safe protection to the circuit.
- Update the regression technique for better accuracy.
- Evaluate the accuracy of the six term model.



E. C. Levy.

Complex-curve fitting.

Automatic Control, IRE Transactions on, AC-4(1):37–44, 1959.



C. K. Sanathanan and J. Koerner.

Transfer function synthesis as a ratio of two complex polynomials.

Automatic Control, IEEE Transactions on, 8(1):56–58, Jan 1963.



Sim surfing.

http://ds.murata.co.jp/software/simsurfing/en-us/ index.html?intcid5=com_xxx_xxx_cmn_nv_xxx.

Questions?